

**Notice of References Cited**

Application/Control No.

10/046,622

Applicant(s)/Patent Under  
Reexamination  
CHEN ET AL.

Examiner

SHAIENDRA - KUMAR

Art Unit

1621

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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	K	US-			
	L	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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